

**Search Notes**

Application/Control No.

10/719,536

Examiner

Ryan Dare

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2186

**SEARCHED**

Class	Subclass	Date	Examiner
711	169	2/3/2006	RD
711	171	2/3/2006	RD
711	172	2/3/2006	RD
711	161	2/3/2006	RD
711	162	2/3/2006	RD
710	30	2/3/2006	RD
710	33	2/3/2006	RD
710	34	2/3/2006	RD
710	35	2/3/2006	RD
710	38	2/3/2006	RD
710	57	2/3/2006	RD
710	29	2/3/2006	RD
709	230	2/3/2006	RD
709	236	2/3/2006	RD

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
711	169	2/3/2006	RD
711	171	2/3/2006	RD
711	172	2/3/2006	RD

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST(US-PGPUB; USPAT, USOCR; EPO; JPO; DERWENT; IBM_TDB)	2/3/2006	RD

RD